Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/691,615	KIM, DO HOON
Examiner	Art Unit
Blane I Jackson	2618

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Subclass	Date	Examiner
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	Subclass	Subclass Date 232.1 06(09/06 234.1

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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